

Kenji Sakurai

List of Publications by Year in descending order

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114
papers

1,253
citations

430874

18
h-index

434195

31
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116
all docs

116
docs citations

116
times ranked

1122
citing authors

#	ARTICLE	IF	CITATIONS
1	Calendar Article. X-Ray Spectrometry, 2022, 51, 178-181.	1.4	0
2	CALENDAR ARTICLE. X-Ray Spectrometry, 2022, 51, 117-120.	1.4	0
3	NEWS ARTICLE. X-Ray Spectrometry, 2022, 51, 116-116.	1.4	0
4	Calendar Article. X-Ray Spectrometry, 2022, 51, 339-343.	1.4	0
5	News Article. X-Ray Spectrometry, 2022, 51, 338-338.	1.4	0
6	NEWS ARTICLE. X-Ray Spectrometry, 2021, 50, 80-80.	1.4	0
7	News Article. X-Ray Spectrometry, 2021, 50, 147-147.	1.4	0
8	Calendar Article. X-Ray Spectrometry, 2021, 50, 148-151.	1.4	0
9	2D real space visualization of d values in polycrystalline bulk materials of different hardness. Journal of Applied Crystallography, 2021, 54, 597-603.	4.5	0
10	Calendar Article. X-Ray Spectrometry, 2021, 50, 239-242.	1.4	0
11	Calendar Article. X-Ray Spectrometry, 2021, 50, 410-412.	1.4	0
12	Book, "Analytical Studies on Metallurgy in Pre-Columbian North of Peru" (Roberto Tj ETQq0 0 0 rgBT /Overlock 10 T 460-460.	1.4	0
13	Calendar Article. X-Ray Spectrometry, 2021, 50, 461-463.	1.4	0
14	The fate of methylmercury through the formation of dimethylmercury sulfide as an intermediate in mice. Scientific Reports, 2021, 11, 17598.	3.3	2
15	Denver X-ray conference award (August 6, 2021). X-Ray Spectrometry, 2021, 50, 524-524.	1.4	0
16	Calendar Article. X-Ray Spectrometry, 2020, 49, 452-455.	1.4	0
17	Virtual Denver X-ray conference ended in success (August 7, 2021). X-Ray Spectrometry, 2020, 49, 690-690.	1.4	0
18	Calendar Article. X-Ray Spectrometry, 2020, 49, 691-694.	1.4	0

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19	News article. X-Ray Spectrometry, 2020, 49, 625-625.	1.4	0
20	Calendar Article. X-Ray Spectrometry, 2020, 49, 626-629.	1.4	0
21	News article. X-Ray Spectrometry, 2020, 49, 533-533.	1.4	0
22	Calendar Article. X-Ray Spectrometry, 2020, 49, 534-536.	1.4	0
23	News Article. X-Ray Spectrometry, 2020, 49, 451-451.	1.4	0
24	One-Amide Thin Films Prepared by Physical Vapor Deposition of Nylon-6 Granules. ACS Applied Polymer Materials, 2020, 2, 1746-1753.	4.4	1
25	Recent Progresses in Nanometer Scale Analysis of Buried Layers and Interfaces in Thin Films by X-rays and Neutrons. Analytical Sciences, 2020, 36, 901-922.	1.6	6
26	Progress of hydrogen gas generation by reaction between iron and steel powder and carbonate water in the temperature range near room temperature. International Journal of Hydrogen Energy, 2020, 45, 13832-13840.	7.1	6
27	Thickness Changes in Temperature-Responsive Poly(<i>N</i> -isopropylacrylamide) Ultrathin Films under Ambient Conditions. ACS Omega, 2019, 4, 12194-12203.	3.5	10
28	Neutron visualization of inhomogeneous buried interfaces in thin films. Scientific Reports, 2019, 9, 571.	3.3	7
29	Slow dynamics in thermal expansion of polyvinyl acetate thin film with interface layer. Polymer Journal, 2019, 51, 1073-1079.	2.7	8
30	Calendar Article. X-Ray Spectrometry, 2019, 48, 163-165.	1.4	0
31	Expanding a polarized synchrotron beam for full-field x-ray fluorescence imaging. Review of Scientific Instruments, 2019, 90, 113704.	1.3	2
32	Antiscattering X-ray fluorescence analysis for large-area samples. Journal of Analytical Atomic Spectrometry, 2019, 34, 2273-2279.	3.0	2
33	Round-robin layer-thickness determination: Toward reliable reference-free X-ray spectrometry. X-Ray Spectrometry, 2019, 48, 3-7.	1.4	4
34	X-ray standing wave technique with spatial resolution: In-plane characterization of surfaces and interfaces by full-field x-ray fluorescence imaging. Physical Review Materials, 2019, 3, .	2.4	3
35	Multi-element X-ray movie imaging with a visible-light CMOS camera. Journal of Synchrotron Radiation, 2019, 26, 230-233.	2.4	9
36	Versatile chemical handling to confine radioactive cesium as stable inorganic crystal. Scientific Reports, 2018, 8, 15051.	3.3	2

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37	Uniaxial Negative Thermal Expansion of Polyvinyl Acetate Thin Film. <i>Langmuir</i> , 2018, 34, 11272-11280.	3.5	7
38	Hadamard coding of time-of-flight neutron reflectogram at grazing incidence. <i>Physica B: Condensed Matter</i> , 2018, 551, 426-430.	2.7	4
39	Novel Neutron Reflectometry with Imaging Capability. <i>Hamon</i> , 2018, 28, 187-191.	0.0	0
40	Thermoresponsive Behavior of Poly(<i>N</i> -isopropylacrylamide) Solid Ultrathin Film under Ordinary Atmospheric Conditions. <i>Chemistry Letters</i> , 2017, 46, 495-498.	1.3	9
41	Optically Reconfigurable Monolayer of Azobenzene Donor Molecules on Oxide Surfaces. <i>Langmuir</i> , 2017, 33, 2157-2168.	3.5	9
42	Seeing elements by visible-light digital camera. <i>Scientific Reports</i> , 2017, 7, 45472.	3.3	13
43	Realtime Observation of Diffusing Elements in a Chemical Garden. <i>ACS Omega</i> , 2017, 2, 4363-4369.	3.5	18
44	Phase Stability of Intermetallic Compound Ce ₃ Al in Mechanical Milling. <i>Metallurgical and Materials Transactions A: Physical Metallurgy and Materials Science</i> , 2017, 48, 5635-5638.	2.2	2
45	Low-temperature Synthesis of Cubic Phase CuFe ₂ O ₄ Powder. <i>Chemistry Letters</i> , 2017, 46, 1493-1496.	1.3	10
46	CCD camera as feasible large-area-size x-ray detector for x-ray fluorescence spectroscopy and imaging. <i>Review of Scientific Instruments</i> , 2017, 88, 063703.	1.3	31
47	Cross-sectional particle measurement in the resonance domain on the substrate through scatterometry. <i>Optics Express</i> , 2017, 25, 26329.	3.4	5
48	Interface-sensitive imaging by an image reconstruction aided X-ray reflectivity technique. <i>Journal of Applied Crystallography</i> , 2017, 50, 712-721.	4.5	9
49	Visualization of Buried Interfaces of Thin Films by Using X-ray Reflection Projections. <i>Hyomen Kagaku</i> , 2017, 38, 448-454.	0.0	2
50	Micro-imaging of buried layers and interfaces in ultrathin films by X-ray reflectivity. <i>Journal of Applied Physics</i> , 2016, 120, .	2.5	9
51	X-ray reflectivity imager with 15 W power X-ray source. <i>Review of Scientific Instruments</i> , 2016, 87, 093709.	1.3	3
52	Combination of projection-based XRF, XAFS and XRD imagings for rapid spatial distribution analysis of a heterogeneous material. <i>Journal of Analytical Atomic Spectrometry</i> , 2016, 31, 1105-1111.	3.0	9
53	Formation of Ultrathin Liesegang Patterns. <i>Langmuir</i> , 2016, 32, 9126-9134.	3.5	16
54	Behavior and Mechanism of Cesium Adsorption on Layered Sodium Silicate Ilerite. <i>Kagaku Kogaku Ronbunshu</i> , 2016, 42, 1-7.	0.3	0

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55	<i>Operando</i> X-ray Fluorescence Imaging for Zinc-based Secondary Batteries. <i>Electrochemistry</i> , 2015, 83, 849-851.	1.4	11
56	Quantitative Determination of Free Lime Amount in Steelmaking Slag by X-ray Diffraction. <i>ISIJ International</i> , 2014, 54, 1334-1337.	1.4	31
57	Erratum to “Quantitative Determination of Free Lime Amount in Steelmaking Slag by X-ray Diffraction” [ISIJ Int. 54(6): 1334–1337 (2014)]. <i>ISIJ International</i> , 2014, 54, 1997-1997.	1.4	0
58	Quick X-ray reflectivity of spherical samples. <i>Powder Diffraction</i> , 2013, 28, 105-111.	0.2	6
59	X-ray Fluorescence Spectrometry with Advanced Synchrotron X-ray Sources. <i>Materia Japan</i> , 2013, 52, 567-571.	0.1	0
60	X-ray Reflection Tomography: A New Tool for Surface Imaging. <i>Analytical Chemistry</i> , 2011, 83, 7600-7602.	6.5	19
61	Hydrophobic switching nature of methylcellulose ultra-thin films: thickness and annealing effects. <i>Journal of Physics Condensed Matter</i> , 2011, 23, 435010.	1.8	8
62	In-situ X-ray reflectivity measurement of polyvinyl acetate thin films during glass transition. <i>IOP Conference Series: Materials Science and Engineering</i> , 2011, 24, 012013.	0.6	10
63	Exploring surfaces and buried interfaces of functional materials by advanced x-ray and neutron techniques. <i>Journal of Physics Condensed Matter</i> , 2010, 22, 470301.	1.8	1
64	In situ Observation of Inhomogeneous Texture During Melting and Freezing of Liquid Gallium by Projection-Type X-ray Diffraction Imaging. <i>Bunseki Kagaku</i> , 2010, 59, 499-511.	0.2	1
65	Structures of Yb nanoparticle thin films grown by deposition in He and N ₂ gas atmospheres: AFM and x-ray reflectivity studies. <i>Journal of Physics Condensed Matter</i> , 2010, 22, 474010.	1.8	5
66	X-ray Diffraction Imaging of Anatase and Rutile. <i>Analytical Chemistry</i> , 2010, 82, 3519-3522.	6.5	78
67	Stability of thermoresponsive methylcellulose thin film: x-ray reflectivity study. <i>X-Ray Spectrometry</i> , 2009, 38, 376-381.	1.4	4
68	Inter-correlation of impurity trace elements in bloodstone rock: X-ray fluorescence mapping studies. <i>Journal of Analytical Atomic Spectrometry</i> , 2009, 24, 1579.	3.0	8
69	Significance of Frequency Analysis in X-ray Reflectivity: Towards analysis which does not depend too much on models. <i>Transactions of the Materials Research Society of Japan</i> , 2008, 33, 523-528.	0.2	23
70	Spectrometer for lanthanides™ K x-ray fluorescence. <i>Review of Scientific Instruments</i> , 2007, 78, 066108.	1.3	3
71	Chemical Data Writing into Metal/oxide Interface: Characterization of Low Dimensional Interface Reactions by I-V Measurements. <i>Materials Research Society Symposia Proceedings</i> , 2007, 1056, 1.	0.1	0
72	Instrumentation for X-ray reflectivity in micro area: present status and future outlook. <i>Journal of Physics: Conference Series</i> , 2007, 83, 012001.	0.4	13

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73	Recent Novel X-ray Reflectivity Techniques: Moving Towards Quicker Measurement to Observe Changes at Surface and Buried Interfaces. Transactions of the Materials Research Society of Japan, 2007, 32, 181-186.	0.2	12
74	Fixation of Carbon Dioxide and Production of Hydrogen Gas by Iron Powder at Room Temperature. Transactions of the Materials Research Society of Japan, 2007, 32, 725-727.	0.2	3
75	A versatile scheme for preparing single-phase yttrium oxysulfate phosphor. Journal of Alloys and Compounds, 2006, 426, 244-246.	5.5	24
76	Measurement of K Series of X-Ray Fluorescence Spectra of Ce and Gd by High Energy X-Ray from Synchrotron Radiation Source. Bunseki Kagaku, 2006, 55, 433-439.	0.2	2
77	Application of In-Plane X-Ray Diffraction Technique for Residual Stress Measurement of TiN Film/WC-Co Alloy. Bunseki Kagaku, 2006, 55, 405-410.	0.2	4
78	Rapid combinatorial screening by synchrotron X-ray imaging. Applied Surface Science, 2006, 252, 2608-2614.	6.1	8
79	Photoinduced Phase Transition of the Coordinationally Unsaturated d9 Metal Centers of Bis(N,N-diethylethylenediamine)copper(II) Perchlorate within the Thermal Hysteresis of the Spin-Exchange Interaction. European Journal of Inorganic Chemistry, 2006, 2006, 1345-1347.	2.0	4
80	Enhancement of CO ₂ Absorbance for Lithium Ferrite—Combinatorial Application of X-Ray Absorption Fine Structure Imaging. Materials Transactions, 2005, 46, 665-668.	1.2	11
81	Combinatorial Fluorescence XAFS Imaging of Manganese Complex Oxides. Chemistry Letters, 2005, 34, 872-873.	1.3	6
82	Determination of interface roughness of Gd films deposited on Si surface using improved wavelet transform of X-ray reflectivity data. Applied Surface Science, 2005, 244, 235-239.	6.1	5
83	Site occupancy determination for manganese in some spinel-type oxides by K ² X-ray fluorescence spectra. Journal of Solid State Chemistry, 2005, 178, 370-375.	2.9	19
84	Bifunctional Photochromism Based on Photoinduced Nitro-Assisted Proton Transfer. Chemistry of Materials, 2005, 17, 5394-5397.	6.7	6
85	Quick atomic-scale structure imaging by synchrotron x-rays: a new tool for probing realistic inhomogeneous systems. Nanotechnology, 2004, 15, S428-S431.	2.6	8
86	Fast X-Ray Fluorescence Camera Combined with Wide Band Pass Monochromatic Synchrotron Beam. AIP Conference Proceedings, 2004, , .	0.4	5
87	XAFS imaging of Tsukuba gabbroic rocks: area analysis of chemical composition and local structure. Journal of Synchrotron Radiation, 2004, 11, 209-213.	2.4	7
88	Pattern transition in Cu—Zn binary electrochemical deposition. Journal of Electroanalytical Chemistry, 2004, 571, 149-158.	3.8	11
89	Mechanochemical formation of novel catalyst for preparing carbon nanotubes: nanocrystalline yttrium aluminum iron perovskite. Scripta Materialia, 2003, 48, 1185-1188.	5.2	14
90	Chemical characterization using relative intensity of manganese K ² and K ²⁵ X-ray fluorescence. Nuclear Instruments & Methods in Physics Research B, 2003, 199, 391-395.	1.4	29

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91	Specular and non-specular X-ray reflection from a single-crystal molybdenum mirror surface. Nuclear Instruments & Methods in Physics Research B, 2003, 199, 139-142.	1.4	1
92	Micro X-ray Fluorescence Imaging without Scans: Toward an Element-Selective Movie. Analytical Chemistry, 2003, 75, 355-359.	6.5	62
93	Wavelength-Dispersive Total-Reflection X-ray Fluorescence with an Efficient Johansson Spectrometer and an Undulator X-ray Source: Detection of 10-16 g-Level Trace Metals. Analytical Chemistry, 2002, 74, 4532-4535.	6.5	48
94	Fast signal processing of a yttrium-aluminum-perovskite:Ce detector for synchrotron x-ray experiments. Review of Scientific Instruments, 2001, 72, 4308-4311.	1.3	19
95	Downsizing of Johansson spectrometer for X-ray fluorescence trace analysis with brilliant undulator source. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2001, 467-468, 1549-1552.	1.6	11
96	Trace Chemical Characterization Using Monochromatic X-ray Undulator Radiation. Analytical Chemistry, 2000, 72, 2613-2617.	6.5	11
97	K-line X-ray fluorescence analysis of high-Z elements. Spectrochimica Acta, Part B: Atomic Spectroscopy, 1999, 54, 29-39.	2.9	17
98	Review on grazing incidence X-ray spectrometry and reflectometry. Spectrochimica Acta, Part B: Atomic Spectroscopy, 1999, 54, 41-82.	2.9	140
99	Total-reflection X-ray fluorescence imaging. Spectrochimica Acta, Part B: Atomic Spectroscopy, 1999, 54, 1497-1503.	2.9	20
100	X-Ray Fluorescence Analysis with a Johansson-type Spectrometer. Japanese Journal of Applied Physics, 1999, 38, 650.	1.5	15
101	A grazing-incidence reflectometer for BL-39XU at SPring-8. Journal of Synchrotron Radiation, 1998, 5, 554-556.	2.4	6
102	Analysis of Specific Interfaces in Thin Films by X-Ray Fluorescence Using Interference Effect in Total Reflection. , 1997, , 695-700.		2
103	Extended x-ray-absorption fine-structure studies on ball-milled powders of the immiscible system Cu-V. Physical Review B, 1992, 46, 5711-5714.	3.2	29
104	Fourier Analysis of Interference Structure in X-Ray Specular Reflection from Thin Films. Japanese Journal of Applied Physics, 1992, 31, L113-L115.	1.5	50
105	Layer Thickness Determination of Thin Films by Grazing Incidence X-Ray Experiments Using Interference Effect. , 1992, , 813-818.		20
106	Layer Thickness Determination of Thin Films by Grazing Incidence X-Ray Experiments using Interference Effect. Advances in X-ray Analysis, 1991, 35, 813-818.	0.0	9
107	Observation of solid-state amorphization in the immiscible system Cu-Ta. Applied Physics Letters, 1990, 57, 2660-2662.	3.3	27
108	SR x-ray fluorescence imaging by image reconstruction technique. Review of Scientific Instruments, 1989, 60, 2458-2461.	1.3	11

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109	Chemical State Mapping by X-Ray Fluorescence Using Absorption Edge Shifts. Japanese Journal of Applied Physics, 1988, 27, L1768-L1771.	1.5	13
110	Analysis of Signal to Background Ratio in Synchrotron Radiation X-Ray Fluorescence. Analytical Sciences, 1988, 4, 3-7.	1.6	14
111	Chemical State Analysis by X-Ray Fluorescence Using Shifts of Iron K Absorption Edge. Analytical Sciences, 1988, 4, 37-42.	1.6	27
112	Chemical State Analysis by X-Ray Fluorescence Using Absorption Edges Shifts. Advances in X-ray Analysis, 1988, 32, 167-176.	0.0	4
113	Near-Surface Analysis of Semiconductor Using Grazing Incidence X-Ray Fluorescence. Advances in X-ray Analysis, 1987, 31, 487-494.	0.0	7
114	Synchrotron radiation excited x-ray fluorescence analysis using total reflection of x-rays. Analytical Chemistry, 1986, 58, 394-397.	6.5	73